

# Spectroscopic Ellipsometer

## Model: SE-2000

SE-2000 is a Spectroscopic Ellipsometer capable of spectroscopic measurements covering a large spectral range from ultraviolet to near infrared within a few seconds. It is suitable for thin films from monolayer to transparent thick films. The analysis software is able to determine the thickness and refractive index of coatings in single or multi-layer stacks.



## Process capabilities

- Standard spectral range :- 245 nm -990 nm.
- Incident angle range :-  $>12^\circ$  to  $90^\circ$ .
- Automatically sample focussing.
- Two chuck configurations are available:
  - Normal chuck (for non-textured Silicon , *glass and textured multicrystalline-Si samples*)
    - Thickness and Refractive index *2-D mapping*. (max substrate size- 8 inch)
    - Thickness and Refractive index point measurements on *multi-layer stack* in addition to mono-layer film.
  - Solar chuck (for *textured mono-Si samples*)
    - Thickness and Refractive index point measurement.